

Design Optimization of Low power VLSI Circuits in Deep Submicron Technology

¹U.Chaitanya, ²K.JayaSankar, ³M.V.Ramana Murthy, ⁴Naraiah.R, ⁵Dr.MD.Javeed Ahammed and ⁶Balaji,B

¹Department of IT, Mahatma Gandhi Institute of Technology, Kokapet (V), Gandipet (M),
HYDERABAD - 500075, TELANGANA

²Department of ECE, Mahatma Gandhi Institute of Technology, Kokapet (V), Gandipet (M),
HYDERABAD - 500075, TELANGANA

³Department of Mathematics and Humanities Mahatma Gandhi Institute of Technology, Kokapet (V),
Gandipet (M), HYDERABAD - 500075, TELANGANA

⁴Asst.Prof, Dept of ECE Narasaraopet Engineering College (Autonomous).Narasaropet, AP-India

⁵Assoc.Prof, Dept of ECE, Narasaraopet Engineering College (Autonomous).Narasaropet, AP-India

⁶Assoc.Prof, Dept of ECE, Koneru Lakshmaiah Education Foundation, Green Fields, Vaddeswaram,
Guntur Dist.522 502-India

Abstract: This paper explores the effect of scaling for low energy and high efficiency of demand and as difficulties of SOI circuits designing. This paper presents the design of a 45 nm SOI MOSFET and surveys the effect on various instrument parameters of the variant of channel doping and gate oxide thickness. Characteristics have been acquired for the suggested MOSFET by considering the most helpful channel doping and TOX values. The Visual TCAD system of used to simulate devices and extract parameters.

Index Terms: CMOS, SOI, low-power, High performance, Circuit design.

I. INTRODUCTION

In telecommunications, audio, video, avionics and a range of mobile electronic consumer products, real-time digital signal processing (DSP) has become increasingly common. With DSP becoming increasingly common[1], there have been growing requirements for multipliers and dividers implementing VLSI hardware that are quicker and more effective in the region. The logarithm emerged from a desire to make arithmetic computations simpler. Multiplication and division[7] can be simplified to the point of addition and subtraction by using logarithms; in addition, energy and root issues are decreased respectively to multiplication and division

[Requirements of performance and power consumption in VLSI circuits over the past few decades, the notion of device scaling has been continuously end [1]. However, conventional device structures are nearer basic physical boundaries, such as bulk MOS transistors [2]. As the size of the device shrink to below the submicron, the boundaries at standard MOS[12] constructions because of the strong at short channel effect and the quantum theorem effect, they become more pronounced, restricting the increase in effectiveness[11]. Therefore, it is vital to look at new device structural model to promote the growth of the VLSI design industry in nano-scale production.. The silicon-on-insulator (SOI) transistors may an outstanding modelling technology to choice for nano-scale circuit design. [1].

SOI technologies to shown mote advantages over bulk silicon technology, such as low parasite junction ability, elevated soft error immunity, removal of CMOS latch-up, no threshold voltage degradation with body effect, and simply device insulation process [3].

Because of its intrinsic structure, SOI has recently drawn specific attention of the short channel impact and improved current drive capacity [4]. at the focus, though, is on the device level. The advantages of SOI transistors

come at an additional door (back-gate) cost, leading in elevated gate capability, dual leakage channels, and hard at front and back gate coupling, complicating the circuits' layout[5].

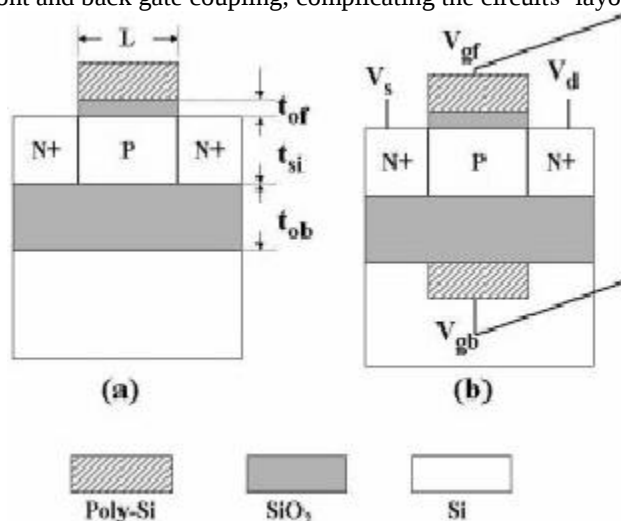


Fig 1: SOI MOSFET

trying to address SOI's design issues in this document. The demand and challenges of SOI circuits in the nano-scale region for low-power high-performance.

II.LITERATURE REVIEW

Fig.1 indicates the cross-section view of a fully depleted SOI transistor in which t_{of} , t_{si} , and t_{ob} represent Oxide at the front gate, film of silicone and oxide density at the back gate[6]. T_{of} is usually considered as the minimum oxide of high performance density. Usually the t_{ob} is bigger than the t_{of} . SOI displays a floating body effect. If the silicon film is thicker than maximum depletion width is considered to be a partially depleted SOI at MOSFET[8-10].

The silicon substratum produces Silicium island with silicon dioxide sandwiched [16]Fig. 2(a). To define the source at drain cavities a reactive ion is used at another low-temperature ELO the remaining islands of silicon as a plant for the development of S / D contact . In the S / D cavities Fig, polysilicon which filled . Wet etching for the removal of dummy doors Fig. 2(e) from above is considered

III .LOW POWER ANALYSIS

3.1: DYNAMIC POWER

The power consumed by a System on Chip is sum dynamic power and as well as static power[18].

Dynamic powers at the power to be dissipated/consumes once the fabrication at active mode[13]. Whenever a device is in active mode the ability dissipated within the device is termed as Static power, however the signal values are unchanged[14]

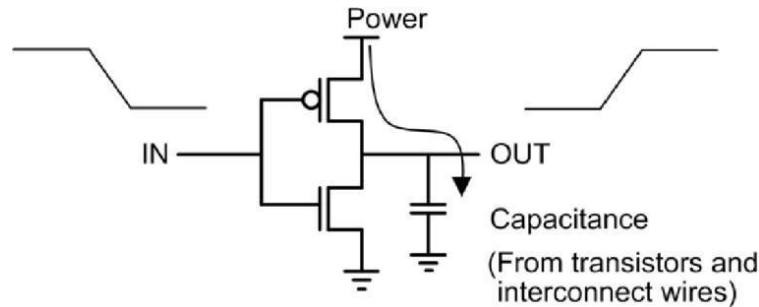


Fig.2: DYNAMIC POWER

$$P_{Short-circuit} = I_{SC} V \dots\dots\dots (2)$$

$$P_{Leakage} = V_{dd} (I_S I_G I_D) \dots\dots\dots (3)$$

$$P_{Total} = P_{Dynamic} + P_{Leakage} \dots\dots\dots (4)$$

$$P_{Total} = (\alpha C_L V_{dd}^2 f_{CLK}) V_{dd} (I_S I_G I_D) \dots\dots (5)$$

The voltage applied to the door terminals regulates the electrical field, which determines the quantity of present flow through the channel. MOSFET[15] Double Gate has two operating modes as shown in Fig.2

IV.RESULATS

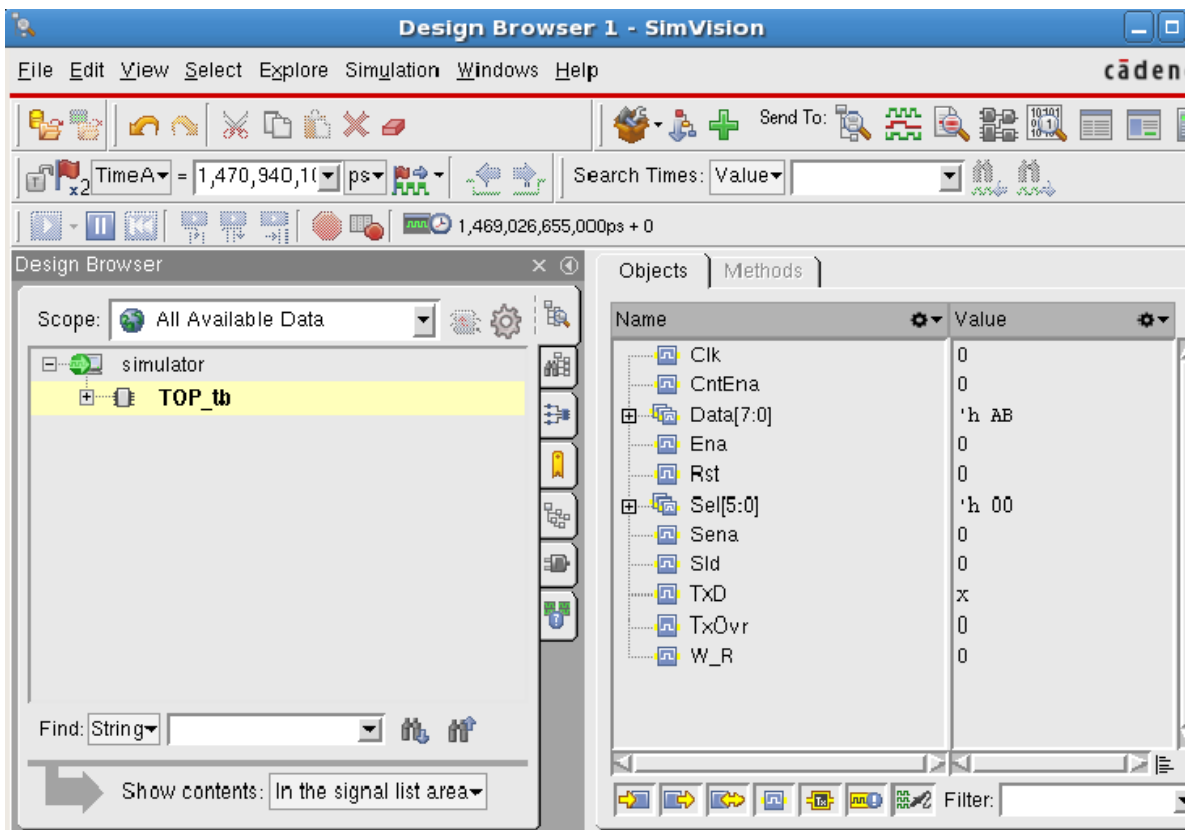


Fig 3: Impact on Channel Doping IOFF

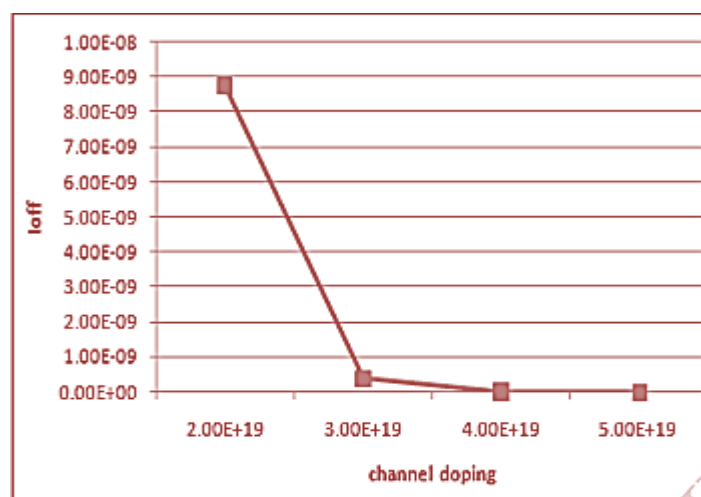


Fig4: Impact on Channel Doping on VTH

V.CONCLUSION

From the above assessment, we can conclude that owing to the brief channel impacts that sink in at smaller door lengths as the systems are scaled down, the off-current develops a significant problem. Channel engineering can be used to control the leakage within permissible limits, but channel doping cannot be enhanced beyond a certain stage as a trade-off between ION and IOFF is essential. High concentrations of doping can lead to degradation of carriers' mobility in the channel.

REFERENCES

- [1] Akshay Kumar Ravirala, Leela Koteswari Bethapudi, Jeevani Kommareddy, Bhanu Sai Thommandru, Sateesh Jasti, Prakash Raju Gorantla, Ashok Puli, Girija Sravani Karumuri, Srinivasa Rao Karumuri, "Design and performance analysis of uniform meander structured RF MEMS capacitive shunt switch along with perforations", *Microsystem Technologies*, Volume 24, Issue 2, pp 901–908, DOI: 10.1007/s00542-017-3403-z, Feb. 2018.
- [2] P. Ashok Kumar, K. Girija Sravani, B. V. S. Sailaja, K. V. Vineetha, Koushik Guha, K. Srinivasa Rao, "Performance analysis of series: shunt configuration based RF MEMS switch for satellite communication applications", *Microsystem Technologies*, Volume 24, Issue 12, pp 4909–4920, to be published, Dec. 2018, DOI: 10.1007/s00542-018-3907-1.
- [3] K. Srinivasa Rao, P. Ashok Kumar, Koushik Guha, B. V. S. Sailaja, K. V. Vineetha, K. L. Baishnab, K. Girija Sravani, "Design and simulation of fixed–fixed flexure type RF MEMS switch for reconfigurable antenna", *Microsystem Technologies*, to be published, <https://doi.org/10.1007/s00542-018-3983-2>.
- [4] K. Girija Sravani, Koushik Guha, K. Srinivasa Rao, Ameen Elsinawi, "Design of a novel structure capacitive RF MEMS switch to improve performance parameters", *IET Circuits, Devices & Systems*. 2019 Jul 12;13(7):1093-101.
- [5] Girija Sravani, K., Koushik Guha, and K. Srinivasa Rao. "A modified proposed capacitance model for step structure capacitive RF MEMS switch by incorporating fringing field effects." *International Journal of Electronics* (2020): 1-22.
- [6] Karumuri Srinivasa Rao, Thalluri Lakshmi Narayana, Koushik Guha & Sravani, Girija. (2018). Fabrication and Characterization of Capacitive RF MEMS Perforated Switch. *IEEE Access*. PP. 1-1. DOI:10.1109/ACCESS.2018.2883353.
- [7] Thalluri, Lakshmi Narayana & Guha, Koushik & Karumuri, Srinivasa Rao & Prasad, G. & Sravani, Girija & Sastry, K. & Kanakala, Appala & Babu, P.. (2020). Perforated serpentine membrane with

- AlN as dielectric material shunt capacitive RF MEMS switch fabrication and characterization. *Microsystem Technologies*. 10.1007/s00542-020-04755-3.
- [8] Sravani, K. Girija, D. Prathyusha, K. Srinivasa Rao, P. Ashok Kumar, G. Sai Lakshmi, Ch Gopi Chand, P. Naveena, Lakshmi Narayana Thalluri, and Koushik Guha. "Design and Performance Analysis of Low Pull-In Voltage of Dimple Type Capacitive RF MEMS Shunt Switch for Ka-Band." *IEEE Access* 7 (2019): 44471-44488.
 - [9] Lakshmi Narayana, T., K. Girija Sravani, and K. Srinivasa Rao. "A micro level electrostatically actuated cantilever and metal contact based series RF MEMS switch for multi-band applications." *Cogent Engineering* 4, no. 1 (2017): 1323367..
 - [10] Rao, K. Srinivasa, P. Naveena, and K. Girija Sravani. "Materials Impact on the Performance Analysis and Optimization of RF MEMS Switch for 5G Reconfigurable Antenna." *Transactions on Electrical and Electronic Materials* 20, no. 4 (2019): 315-327.
 - [11] Sravani, K. Girija, and K. Srinivasa Rao. "Analysis of RF MEMS shunt capacitive switch with uniform and non-uniform meanders." *Microsystem Technologies* 24, no. 2 (2018): 1309-1315.
 - [12] Sravani, K. Girija, Koushik Guha, and K. Srinivasa Rao. "Analysis on selection of beam material for novel step structured RF-MEMS switch used for satellite communication applications." *Transactions on Electrical and Electronic Materials* 19, no. 6 (2018): 467-474.
 - [13] Vijaya Prasad K., Kishore P.V.V., Srinivasa Rao O. (2019), 'Skeleton based viewinvariant human action recognition using convolutional neural networks', *International Journal of Recent Technology and Engineering*, 8(2), PP.4860-4867
 - [14] Maity R., Maity N.P., Srinivasa Rao K., Guha K., Baishya S. (2018) , 'A newcompact analytical model of nanoelectromechanical systems-based capacitive micromachined ultrasonic transducers for pulse echo imaging', *Journal of Computational Electronics*, 17 (3), PP. 1334- 1342
 - [15] Aditya M, I Veeraghava Rao, B. Balaji, John Philip B, Ajay Nagendra N, S Vamsee Krishna," A Novel Low-Power 5th order Analog to Digital Converter for Biomedical Applications", *IJITEE*, ISSN: 2278-3075, Volume-8 Issue-7, PP: 217-220, May, 2019
 - [16] B. Balaji, M. Aditya, G. Adithya, M. Sai Priyanka, V. V. S. S. K. Ayyappa Vijay, K. Chandu,: Implementation of Low-Power 1-Bit Hybrid Full adder with Reduced Area", *IJITEE*, ISSN: 2278-3075, Volume-8 Issue-7, PP:61-64, May, 2019.
 - [17] B.Balaji, N Ajaynagendra, Erigela Radhamma, A Krishna Murthy, M Lakshmana Kumar," Design of Efficient 16 Bit Crc with Optimized Power and Area in Vlsi Circuits",*IJITEE*, ISSN: 2278-3075, Volume-8 Issue-8, PP:87-91 June, 2019
 - [18] Naraiah, R., Balaji, B., Radhamma, E., Udutha, R."Delay Approximation Model for Prime Speed Interconnects in Current Mode" *IJITEE*, ISSN: 2278-3075, Volume-8 Issue-9, PP:3090-3093, July 2019
 - [19] Kumar, P.A., Rao, K.S., Balaji, B. *et al.* Low Pull-in-Voltage RF-MEMS Shunt Switch for 5G Millimeter Wave Applications. *Trans. Electr. Electron. Mater.* (2021). <https://doi.org/10.1007/s42341-021-00304-5-4867>